

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
S1	366	700/110.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/07/14 17:15
S2	1296	700/121.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/07/14 17:15
S3	1160	S2 not S1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/07/14 17:15
S4	14	S3 and (route same database)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/07/14 17:16
S5	17	S3 and (fault adj analysis)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/07/14 17:16
S6	1	S3 and (fault adj correction)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/07/14 17:17
S7	74	S3 and ((fault error) same correction)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/07/14 17:18
S8	25	"6763130".pn. "6496596".pn. "5761064".pn. "6240329".pn. "6408219".pn. "6185511".pn. "6542830".pn. "5963881".pn. "6456899".pn. "6366824".pn. "6556959".pn. "6314379".pn.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/07/14 17:26
S9	1	S8 and (route)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/07/14 17:19

S10	10	S8 and tool	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/07/14 17:24
S11	1	S8 and (source adj defect)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/07/14 17:27
S12	2	S3 and (source adj defect)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/07/14 17:26
S13	7	S8 and (source samedefect)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/07/14 17:27
S14	6	S8 and (source same defect)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/07/14 17:27



[Web](#) [Images](#) [Groups](#) [News](#) [Froogle](#) [Local](#) [more »](#)

mes defect source

Search

[Advanced Search](#)
[Preferences](#)

☐ Search the Web ☒ Search English and German pages

Web

Results 1 - 10 of about **69,200 English and German pages** for **mes defect source**. (0.27 seconds)

MICRO: Defect/Yield Analysis and Metrology - Poag(July 2000)

Data consistency and rapid response to yield-limiting **defect** excursions are among ... has been helpful occurred during a **defect source** analysis exercise. ...
www.micromagazine.com/archive/00/07/poag.html - 38k - [Cached](#) - [Similar pages](#)

SCS-Mag.com: Hewlett-Packard's MES Kit

... Saves Millions in IT Costs and Boosts Production 120% with Open-Source MES.
... file server, UNIX, integration, **defect**, tracking, reporting, scheduling, ...
www.scs-mag.com/reader/2003/2003_09/hewl0903/ - 7k - [Cached](#) - [Similar pages](#)

Quality Digest Magazine

An MES is a rich **source** of detailed yet contextualized information that allows Six Sigma programs to take root and flourish. Improving Six Sigma results ...
www.qualitydigest.com/june04/articles/04_article.shtml - 40k - [Cached](#) - [Similar pages](#)

Manufacturing Execution Systems: Part 2

Should a **defect** occur, the MES makes it easy to identify where the problem arose, ... at the time of the event and as close to the data **source** as possible. ...
www.qualitydigest.com/sep99/html/mes2.html - 33k - [Cached](#) - [Similar pages](#)

[PDF] 70846-3 27..30

File Format: PDF/Adobe Acrobat
only patient with MES, the **source** of these. microemboli was most probably the heart.
The. absence of MES cannot be attributed to technical ...
www.blackwell-synergy.com/doi/abs/10.1034/j.1600-0404.2000.102001027.x - [Similar pages](#)

Investigation Process Research Reference Library

I have discerned a number of misrepresentation of the MES investigation system in the ... please reference this site as the **source**, and observe copyrights. ...
www.iprr.org/index.shtml - 15k - [Cached](#) - [Similar pages](#)

CAST - Research - System Engineering

A Manufacturing Execution System (MES) has been developed by CAST to provide the enterprises with an ... Company Profile (**Source**: www.kinpaq.com.tw) ...
www.cast.itri.org.tw/eng/research/se/mes.jsp - 21k - Jul 13, 2005 - [Cached](#) - [Similar pages](#)

[PDF] Inforeverest, IET The partner for your excellence IET MES ...

File Format: PDF/Adobe Acrobat - [View as HTML](#)
lot of information needs to be communicated between MES and ERP. ... different AQL sampling rules, QC Items, **defect** items and **defect** causes to different ...
supplychain.ittoolbox.com/browse.asp?c=SCMPeerPublishing&r=http://hosteddocs.ittoolbox.com%2FJC051305.pdf - [Similar pages](#)

[PDF] Don't Overlook Manufacturing Execution in Your Product Lifecycle ...

File Format: PDF/Adobe Acrobat
data from the **source** (ie, the machines. and processes that produced it) and ...
For example, the MES may collect a. higher than normal **defect** rate from a ...

www.visiprise.com/pdf/dont_overlook_manufacturing.pdf - [Similar pages](#)

UK J2Ee Defect Tracking - Software, Hardware, Services and ...

Your search for keyword: UK J2Ee Defect Tracking returned 669 results. ...

It also allows Perforce change lists and related source file names to be ...

knowledgestorm.co.uk/search/keyword/ksuk/

[UK%20J2Ee%20Defect%20Tracking/UK%20J2Ee%20Defect%20Tracking](#) - 106k - [Cached](#) - [Similar pages](#)

Google

Result Page: [1](#) [2](#) [3](#) [4](#) [5](#) [6](#) [7](#) [8](#) [9](#) [10](#) [Next](#)



[Search within results](#) | [Language Tools](#) | [Search Tips](#) | [Dissatisfied? Help us improve](#)

[Google Home](#) - [Advertising Programs](#) - [Business Solutions](#) - [About Google](#)

©2005 Google



[Web](#) [Images](#) [Groups](#) [News](#) [Froogle](#) [Local](#) [more »](#)

mes defect source wafer

Search

[Advanced Search](#)
[Preferences](#)

☐ Search the Web ☒ Search English and German pages

Web Results 1 - 10 of about **721 English and German** pages for **mes defect source wafer**. (0.24 seconds)

MICRO: Defect/Yield Analysis and Metrology - Poag(July 2000)

All patterned-wafer defect inspection tools have onboard ADC. ... of the analysis module has been helpful occurred during a defect source analysis exercise. ...
www.micromagazine.com/archive/00/07/poag.html - 38k - [Cached](#) - [Similar pages](#)

MICRO:Archive:Back Issue TOC

... install MES software in Dresden; Empak to expand line of wafer-handling products
... Products: Spin coating valve, XRF wafer analyzer, defect detection ...
www.micromagazine.com/archive/1999.html - 49k - [Cached](#) - [Similar pages](#)

Revenue Losses from Wafer Defects - Semiconductor Factory ...

ECNext Knowledge Center Your source for in-depth & complete analysis of the IC Market. ... Market Shares of Automated Wafer Transfer Suppliers ...
informationnet.ecnext.com/coms2/summary_0243-390_ITM - 22k - [Cached](#) - [Similar pages](#)

Tool connectivity

Existing defect control software takes a similar approach. ... The MES might keep track of each individual wafer move, while leaving interaction with the ...
www.thinfilmmfg.com/subscribers/ Subscriber01/connect.htm - 14k - [Cached](#) - [Similar pages](#)

DMSVision - Wafer Manufacturing Inspection and Metrology

Inspection, Metrology and Data Analysis Solutions for Wafer ... By automating defect analysis with flexible alarms, DMSVision allows time to be spent ...
www.augusttech.com/products/dmsvision.asp - 52k - Jul 14, 2005 - [Cached](#) - [Similar pages](#)

Semiconductor International - Applying a Defect Spatial Signature ...

Automated defect inspection can generate hundreds of wafer-inspection records ... The system will feed the MES system to auto-alarm on specific signatures, ...
www.reed-electronics.com/semiconductor/ article/CA604355?pubdate=6%2F1%2F2005&spacedesc=webex - [Similar pages](#)

Future Fab Intl.

When looking at just the work flow portion of metrology, the MES/AMHS systems ... Defect control metrology most readily comes to mind in providing examples ...
www.future-fab.com/documents.asp?grID=216&d_ID=916 - 71k - [Cached](#) - [Similar pages](#)

SEMATECH Dictionary: M to Mes

an instruction in a source language designated to be replaced by a defined ... in the measurement of wafer flatness, the largest of the absolute values of ...
www.sematech.org/resources/ publishing/dictionary/m_to_mes.htm - 47k - Jul 13, 2005 - [Cached](#) - [Similar pages](#)

SEMATECH Dictionary: Pi to Pg

a wafer that is sent ahead of the parent lot to ensure that ... 1 : minute defect or void in a film, mask, or resist, usually the result of contaminants. ...
www.sematech.org/resources/ publishing/dictionary/pi_to_pq.htm - 42k - Jul 13, 2005 - [Cached](#) - [Similar pages](#)
[[More results from www.sematech.org](#)]

[PDF] Inforeverest, IET The partner for your excellence IET MES ...

File Format: PDF/Adobe Acrobat - [View as HTML](#)

different AQL sampling rules, QC Items, **defect** items and **defect** causes to ...

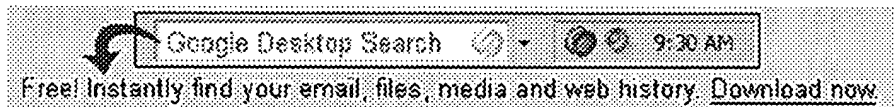
6 IET MES for IC Packaging & Testing. **Wafer. Wafer Sort. Laser Repair ...**

supplychain.ittoolbox.com/browse.asp?c=SCMPeerPublishing&

r=http://hosteddocs.ittoolbox.com%2FJC051305.pdf - [Similar pages](#)

Google

Result Page: [1](#) [2](#) [3](#) [4](#) [5](#) [6](#) [7](#) [8](#) [9](#) [10](#) [Next](#)



mes defect source wafer

Search

[Search within results](#) | [Language Tools](#) | [Search Tips](#) | [Dissatisfied? Help us improve](#)

[Google Home](#) - [Advertising Programs](#) - [Business Solutions](#) - [About Google](#)

©2005 Google